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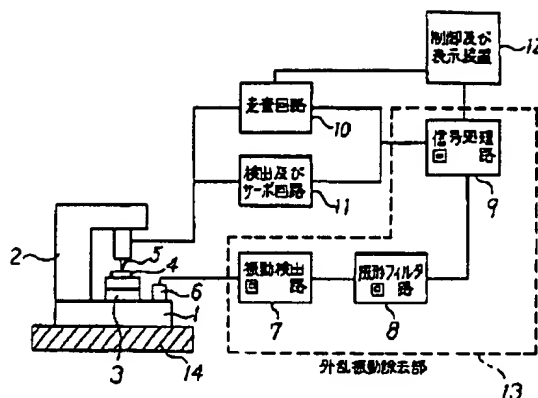
APPLICATION DATE : 19-09-91
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TITLE : SCANNING TYPE MICROSCOPE



ABSTRACT : PURPOSE: To make it possible to perform observation in high resolution and to reduce restrictions on an installing environment by removing the disturbance vibration component from the observed information of the surface of a sample with an electric signal without using a mechanical vibration removing device when a scanning type microscope is used.

CONSTITUTION: A vibration detector 5 is fixed to a scanning-microscope main body 1. The detected vibration is converted into the relative vibration displacement of a probe 3 and a sample 4 with a molded filter circuit 8. This information and the data from a scanning circuit 10 and a detection and servo circuit 11 are inputted into a signal processing circuit 9. Thus, the disturbance vibration component is removed from the observed information of the sample surface.

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